

External NTC calibration RD53B SCC Rev 1.4

Ext NTC (Negative Temperature Coefficient Thermistor)

A wire bond pad sources a known current that is sent to an external NTC for silicon detector **temperature measurement**.

$$R = (V_{mux2} - V_{mux30}) / ((I_{mux9} - V_{mux30})/10k)$$

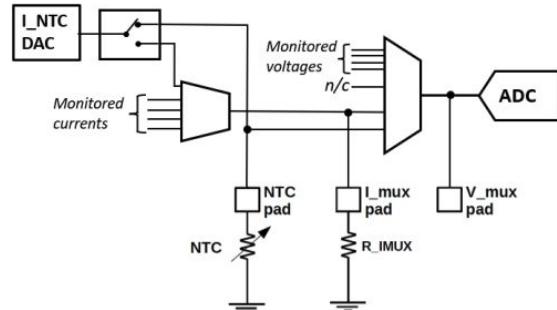
$$T = 1/(A + B \ln R + C (\ln R)^3) \quad \text{Steinhart–Hart equation}$$

A, B, C taken from "NtcCalPar" in chip config.

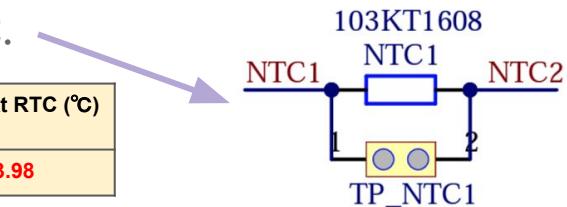
Ext NTC

Use an external multimeter to directly measure resistance of NTC.

I _{mux 9} (V)	V _{mux 3} (V)	V _{mux 30} (V)	R Ext RTC (Ω)	R Ext Ext RTC (Ω)	T Ext RTC (°C)	T Ext Ext RTC (°C)
0.42768	0.38984	0.003153	9108.65504431991	5040.5	27.43	43.98



V _{mux 2}	NTC_PAD voltage
I _{mux 9}	NTC_PAD current
V _{mux 30}	GND



MOS temperature sensor RD53B SCC Rev 1.4

Transistor Sensor

The voltage V_D across a diode shows a Complementary-To-Absolute Temperature variation.

$$\Delta V_D = V_D(R \times I_{bias}) - V_D(I_{bias}) = N_f \times k_B T / q \times \ln(R)$$

Proportional-To-Absolute Temperature ideality factor (1 for an ideal diode)

Absolute temperature: $T = \Delta V_D \times q / (N_f \times k_B \times \ln(R))$ $R=15$ fixed

Measurement [link to instructions](#) [link to Yarr code](#)

- Collect readings from Vmux 14 (ana. sldo), 16 (dig. sldo), and 18 (center).
- Set bias selection switch "MonSensSldoDigSelBias" to 0 (1) for IBAIS ($R \times I_{bias}$).
- For each value (0-15) of the dynamic element matching bits "MonSensSldoDigDem", measure V_D through Vmux and take average.

